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GB/T 32280-2015

Test method for warp of silicon wafers - Automated non-contact scanning method

硅片翘曲度测试 自动非接触扫描法

(English Translation)

Issued on: December 10, 2015

Issued by: General Administration of Quality Supervision, Inspection and Quarantine of the People's Republic of China;
Standardization Administration of China

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Document data

1 Document data

Sector: National standard (Recommended).

Issuing body: General Administration of Quality Supervision, Inspection and Quarantine of the People's Republic of China; Standardization Administration of China.

Date of issue: 2015-12-10.

Date of implementation: 2017-01-01.

Status: obsolete, replaced by GB/T 32280-2022.

Preview: page 2 of 2 shown, full document available. Complete English PDF, instant download:
https://chinastandards.org/standards/gb-t-32280-2015